

Form PTO-1449

#### INFORMATION DISCLOSURE CITATION

Attorney Docket No. S243 1020.1	Serial No. 10/053,859
Applicant Goodson, et al.	
Filing Date	Group

		(Use several sheets if necessary)			Filing Date 01/19/02	<b>;</b>	Grou 3743		
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M	A	5,880,071	03/99	Parce et al.		204	453		
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· ph		В	transfer coefficie	nts", B	ing of compact micro ler, et al American S vision, DSC, 1990, v	Society of Mec							
m		С			of a cross flow micro Systems; Dec 2000;			is et	al., Jou	rnal of			
"Two-phase electronic cooling using mini-channel and micro-channel heat sinks: Part I criteria and heat diffusion constraints", Bowers. et al., Transactions of the ASME. Dec v.116. p.290-297													
M		E	I .		oosmotic flow in micical; May 15, 2001; v		-	', Mc	orthy 6	et al., Ser	isors		
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M		AA			rm electroosmosis", ( r Optical Engineering	, -		_	PIE -	
m		AB		'Bibliography of liquid cooled heat sinks for thermal enhancement of electronic packages, Shaukatul I ah, IEEE Semiconductor Thermal Measurement and Management Symposium, 1999, p.231-245						
m		AC	"Transient temperature performance of an integrated micro-thermal system", Jiang, et al., Journal of Micromechanics and Microengineering, Sep. 2000, v.10, p.466-476							
M		AD	'Phase change in microchannel heat sinks with integrated temperature sensors', .Jiang. et al., Journal of Microelectromechanical Systems, 1999, v.8. no. 4, p.358-365							
\M	AE "Electroosmotic pumping and electrophoretic separations for miniaturized chemical analysis systems", Manz. et al., j. Micrornech Microeng., 1994, p.257-265									

\* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

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	Attorney Docket No. S243 1020.1	Serial No. 10/053,859
	Applicant Goodson, et al.	
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Examiner Initials	Item	Document Number	Date	° Name	Class	Subclass	Filing Date If Appropriate
1/1	AA	5,869,894	02/97	Degani, et al.	257	723	
`\	AB	5,901,040	05/99	Cromwell, et al.	361	704	
	AC	6,025,208	02/00	Chui, et al.	438	50	
	AD	6,052,287	04/00	Palmer, et al.	361	767	
	AE	6,133,631	10/00	Belady	257	714	
	AF	6,137,693	10/00	Schwiebert, et al.	361	803	
	AG	6,191,945	02/01	Belady, et al.	361	704	
	AH	6,285,550	09/01	Belady	361	704	
M	AI	6,297,551	10/01	Dudderar, et al.	257	723	

#### FOREIGN PATENT DOCUMENTS

				Document Date Country Number		Country	Class	Subclass	Translation	
		·				·	Yes	No		
m	AJ	9.7212126.9	07/98	China	B01D	61/42	X			
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#### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

()aa	AK	"Micro Channel Heat Exchanger for Cooling Electrical Equipment," Kawano, et al., American Society of
1M		Mechanical Engineers, Heat Transfer Division, (Publication) HTD; 1998; v. 361 – 3, p. 173 - 180

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Attorney Docket No. S243 1020.1	Serial No. 10/053,859
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				U.S.	PATENT DOCUMENTS			
Exam: Initia		Item	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
1		BA	4,009,423	02/77	Wilson	361	385	
		BB	4,067,237	01/78	Arcella	73	204	
		BC	4,120,019	10/78	Arii, et al.	361	385	
		BD	4,151,548	04/79	Klein, et al.	357	82	
		BE	4,392,362	07/83	Little	62	514	
		BF	4,638,854	07/83	Noren	165	76	
		BG	4,675,783	06/87	Murase, et al.	361	385	
		ВН	4,697,427	10/87	Niggemann, et al.	62	119	
M	(	BI	4,829,432	05/89	Hershberger, et al.	361	424	. <u>.</u>

# Document Number Date Country Class Subclass Translation Yes No

FOREIGN PATENT DOCUMENTS

#### OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

t- 1 a	BJ	'Experimental Study on an Enhanced Microchannel Heat Sink for Microelectronics Applications," Keska, et al.,
m		American Society of Mechanical Engineers, EEP; 1999, v. 26 (2), p. 1235 - 1259

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<sup>\*</sup> EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.



Attorney Docket No. Serial No. S243 1020.1 10/053,859 **Applicant** INFORMATION DISCLOSURE CITATION Goodson, et al. Filing Date (Use several sheets if necessary) Group 01/19/02 3743 U.S. PATENT DOCUMENTS Examiner Item Document Class Subclass Filing Date Date Name If Appropriate **Initials** Number 08/89 Sturgeon 363 20 CA | 4,858,093 07/90 Clark 80.4 CB 4,938,280 165 08/90 Peterson, et al. 32 165 CC 4,951,740 CD 4,975,825 12/90 Huss, et al. 363 141 4/91 274 CE | 5,010,292 Lyle, Jr. 323 07/92 Bowen, et al. 439 194 CF | 5,131,859 CG | 5,144,531 09/92 Go, et al. 361 382 11/92 Currie 385 CH 5,162,974 361 CI 5,199,165 4/93 Crawford, et al. 29 846 FOREIGN PATENT DOCUMENTS Document Date Country Class Subclass Translation Number Yes No OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) 'High Performance Forced Air Cooling Scheme Employing Microchannel Heat Exchangers," Kleiner, et al., IEEE Transactions on Components, Packaging, and Manufacturing Tech., Part A, Dec 1995; v. 18, no. 4, p. 795-804 \* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant. **EXAMINER'S SIGNATURE:** DATE CONSIDERED:



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m	DA	5,229,915	07/93	Ishibashi, et al.	. =		361	38	85	<u></u>	
	DB	5,311,397	05/94	Harshberger, et al.			361	6	83		
	DC	5,313,099	05/94	Tata, et al.			287	7	17		
	DD	5,339,214	08/94	Nelson			361	69	95		
	DE	5,365,749	11/94	Porter			62	25	9.2		
	DF	5,461,541	10/95	Wentland, Jr. et al.			361	70	07		
	DG	5,471,850	12/95	Cowans			62	22	23		
4	DH	5,504,650	04/96	Katsui, et al.			361	69	97		
M	DI	5,504,924	04/96	Ohashi, et al.			375	80	00		
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M	C	onference: Intersociety Co	onference	on Thermal Phenomen	in Electr	onic Sysems	- I-The	rm '92	, 2/5 –	8/92, Aust	in, TX
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M	EA	5,508,908	04/96	Kazama, et al.		363	1	41		
	ЕВ	5,513,070	04/96	Xie, et al.		361	7	00		
	EC	5,544,412	08/96	Romero, et al.		29	8	32		
	ED	5,565,705	10/96	Romero, et al.		257	7	18		
	EE	5,579,827	12/96	Chung		165	80	0.3		
	EF	5,598,320	1/97	Toedtman, et al.	,	361	6	87		
	EG	5,608,262	3/97	Degani, et al.	-	257	7	23		
A	ЕН	5,621,635	4/97	Takiar		363	1-	41		
M	EI	5,646,828	7/97	Degani, et al.		361	7	15		
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<b>b</b> .	EJ	"Heat Transfer of Microstr	ructures f	or Integrated Circuits," K	Coh, et al. Internation	onal Com	nunica	itions in	Heat and	
TM		Mass Transfer; Jan – Feb 1	1986; v. 1	3, no. 1, p. 89 – 98.						
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AM	FA	6,034,425	03/00	Chiang, et al.		257	697		
	FB	6,121,682	09/00	Kim		257	723	T	
	FC	6,127,726	10/00	Bright, et al.		257	691		
	FD	6,154,370	11/00	Degani, et al.		361	761		
	FE	6,201,302	03/01	Tzu		257	724		
	FF	6,204,562	03/01	Ho, et al.		257	777		
	FG	6,215,193	04/01	Tao, et al.		257	777		
A	FH	6,268,660	07/01	Dhong, et al		257	774		
M	FI	6,278,190	08/01	Tomita		257	777		
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	FJ	'Convection Cooling o	of Microelect	tronic Chips," Konecni, et	t al., Conference: I	ntersociety	y Conference	on Therma	ıl
M.		Phenomena in Electror	nic Systems -	- I-Therm '92, 2/5 – 8/92,	, Austin, Texas				
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M	GA	6,335,566	01/02	Hirashima, et al.		257	6	86		
	GB	6,344,682	02/02	Tomita		257	6	86		
	GC	5,965,813	10/99	Wan, et al.		73	20	4.26		
	GD	5,965,001	10/99	Chow, et al.		204	6	00		
	GE	5,978,220	11/99	Frey, et al.		361	6	99		
	GF	5,997,713	12/99	Beetz, Jr., et al.		205	1	24		<u> </u>
	GG	5,998,240	12/99	Hamilton, et al.		438	1	22		
V	GH	6,007,309	12/99	Hartley		417	3	22		
-m	GI	6,010,316	01/00	Haller, et al.		417	3	22		
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M		Mechanical Systems (ME	MS); 200	1; p. 422 - 426						
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1	Ņ	НА	5,801,442	09/98	Hamilton, et al.		257	7	/14		
1		НВ	5,835,345	11/98	Staskus, et al.		361	$\epsilon$	599		
		HC	5,836,750	11/98	Cabuz		417	3	322		
		HD	5,858,188	01/99	Soane, et al.		204	4	154		
		HE	5,863,708	01/99	Zanzucchi, et al.		430	3	320		
		HF	5,870,823	02/99	Bezama, et al.		29	8	348		
		HG	5,880,524	03/99	Xie		257	7	704		
4		НН	5,901,037	05/99	Hamilton, et al.		361	6	599		
1	M	HI	5,940,270	08/99	Pucket		361	6	599		
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		НЈ	"Simulation of Micro-Char	nnel Hea	t Sinks for Optoelectronic	: Microsystems," K	Creutz, et a	al., M	icroelect	ronics Jou	rnal;
P	M	3	October 2000; v. 31, no. 9,	, p. 787 –	- 790	· ·					•
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Attorney Docket No. Serial No. S243 1020.1 10/053,859 **Applicant** INFORMATION DISCLOSURE CITATION Goodson, et al. (Use several sheets if necessary) Filing Date Group 3743 01/19/02 U.S. PATENT DOCUMENTS Subclass Filing Date Examiner Item Document Name Class Date **Initials** Number If Appropriate 01/00 Paul, et al. 204 IA 6,013,164 450 6,019,882 02/00 Paul, et al. 204. 450  $\mathbf{I}\mathbf{B}$ 04/00 |Soane, et al. 204 601 IC 6.054,034 702 08/00 Matzke, et al. 438  $\mathbf{ID}$ 6.096,656 08/00 Fuesser, et al. 29 890.03 Œ 6,101,715 IF 6,129,145 10/00 Yamamoto, et al. 165 168 11/00 Lee, et al. 417 50 IG | 6,146,103 IH 11/00 |Chang 361 699 6,154,363 01/01 |Chow, et al. 435 6 II 6,174,675 FOREIGN PATENT DOCUMENTS Translation Document Class Subclass Date Country Number Yes No OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.) "Fabrication of Very Smooth Walls and Bottoms of Silicon Microchannels for Heat Dissipation of Semiconductor Devices," Dwivedi, et al., Microelectronics Journal; 2000; v. 31, no. 6, p. 405 – 410. \* EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant. **EXAMINER'S SIGNATURE:** DATE CONSIDERED:



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M	JA	6,210,986	01/01	Arnold, et al.		438		42			
	ЈВ	6,216,343	04/01	Leland, et al.		29	890	0.032			
	JC	6,227,809	05/01	Forster, et al.		417		53			
	JD.	6,234,240	05/01	Cheon		165	8	0.3			
	JE	6,238,538	05/01	Parce, et al.		204	6	500			
	JF	2001/0016985	08/21	Insley, et al.		29	8,90	0.039			
	JG	6,287,440	09/01	Arnold, et al.	Arnold, et al.						
1	ЛН	2001/0024820	09/01	Mastromatteo, et a	l.	435	28	87.2			
1/1	JI	6,301,109	10/01	Chu, et al.		361	6	590			
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M	KA	6,313,992	11/01	Hildebrandt		361	70	00		
	КВ	2001/0044155	11/01	Paul, et al.		436	16	51		
	KC	6,321,791	11/01	Chow		137	83	33		
	KD	6,322,753	11/01	Lindberg, et al.		422	19	92		
	KE	6,324,058	11/01	Hsiao	361	699		. <u>-</u>	-	
	KF	2001/0046703	11/01	Burns, et al.	435	303.1				
	KG	3,923,426	12/75	Theeuwes	417	48				
V	KH	4,312,012	01/82	Frieser, et al.		357	357 82			
M	KI	4,450,472	05/84	Tuckerman, et al.	`	357	8:	2		
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	KJ	'Silicon Micromachining	for Integr	rated Microsystems," Esas	shi, Vacuum; Jun -	- Aug 199	6, v. 47	, no. 6	- 8	
M		pp. 469 - 474				***************************************				
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		LC	4,567,505	01/86	Pease, et al.		357	81			
		LD	4,573,067	02/86	Tuckerman, et al.		357	82	, (		
		LE	4,758,926	07/88	Herrell, et al.		361	38:	5		
		LF	4,868,712	09/99	Woodman	·	361	38	8		
A		LG	4,894,709	01/90	Phillips, et al.		357	82			
7	η	LH	4,908,112	03/90	Pace		204	29	9		
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M	MA	5,016,138	05/91	Woodman		361	381		
	МВ	5,057,908	10/91	Weber		357	81		
	MC	5,070,040	12/91	Pankove		437	209	·. <u>-</u>	
	MD	5,083,194	01/92	Bartilson		357	. 81		
	ME	5,096,388	03/92	Weinberg		417	322		
	MF	5,099,311	03/92	Bonde, et al.		357	82		
	MG	5,125,451	06/92	Matthews		165	80.4		
4	МН	5,099,910	03/92	Walpole, et al.		165	80.4		
M	MI	5,131,233	07/92	Cray, et al.	-	62	64		
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		NB	5,218,515	06/93	Bernhardt ·		361	3	85		
		NC	5,219,278	06/93	Van Lintel		417	4	13		
		ND	5,230,564	07/93	Bartilson, et al.		374	1	78		
		NE	5,232,047	08/93	Matthews		165	1	68	_	
		NF	5,239,200	08/93	Messina, et al.		257	7	14		
		NG	5,263,251	11/93	Matthews		29	840	0.036		
V		NH	5,274,920	01/94	Matthews		29	890	0.039		
1	1	NI	5,281,026	01/94	Bartilson, et al.		374	1	43		
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	ОВ	5,317,805	06/94	Hoopman, et al.		29	890.	.03		
	ос	5,325,265	06/94	Turlik, et al.		361	70	2	_	
	OD	5,336,062	08/94	Richter		417	41	3	-	_
	OE	5,383,340	01/95	Larson, et al.		62	259	9.2		
	OF	5,427,174	06/95	Lomolino, Sr., et al.		165	1			•
	OG	5,436,793	07/95	Sanwo, et al.		361	68	9		
1	ОН	5,459,099	10/95	Hsu		437	18	0		
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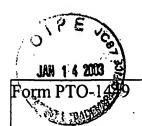
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1	M	QA	5,759,014	06/98	Van Lintel		417	4	13.3	_	
		QB	5,763,951	06/98	Hamilton, et al.		<b>257</b> .	7	714		
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		QE	6,337,794	01/02	Agonafer, et al.		361	•	590	·	
		QF	5,942,093	08/99	Rakestraw, et al.		204	4	<b>1</b> 50		
1		QG	6,351,384	02/02	Daikoku, et al.		361	7	704		
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M	RA	6,068,752	05/00	Dubrow, et al.		204	604		
77	RB	6,090,251	07/00	Sundberg, et al.		204	453		
	RC	6,100,541	08/00	Nagle, et al.		250	573		
	RD	6171,067	01/01	Parce		417	48		
	RE	6,176,962	01/01	Soane, et al.		156	. 292		
	RF	6,210,986	04/01	Arnold, et al.		438	42		
	RG	6,221,226	04/01	Kopf-Sill		204	602		
	RH	6,277,257	08/01	Paul, et al.		204	450		
V	RI	5,216,580	09/93	Davidson, et al.		361	385		
M	RJ	5,560,423	10/96	Larson, et al.		165	104.26		
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,	SC	"Parametric optimization Transactions on Compor	n of mul nents an	tichanneled heat sinks d Packaging Technolo	for VLSI chip cogies; March 2001	ooling", N ; v.24, no	/uraka 5.1, p.2	mi et a 2-9	at., IEEE	
		"Experimental investigat International Journal of I						ts", Pe	ng et al.,	
		'Forced convection and : International Journal of I						mels",	Peng et a	1.,
		"Enhancing the critical h Transfer; 1998; v.5, no.3			l surfaces", Peng	et al., Joi	ırnal o	f Enha	nced Hea	t
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	UB "Single-phase flow thermal performance characteristics of a parallel micro-channel heat exchanger", Ravigururajan et al., American Society of Mechanical Engineers, Heat Transfer Division, (Publication) HTD; 1996; v.329, no. 7, p.157-166										
		"Effect of heat flux on t exchanger", Ravigurura (Publication) HTD; 199	an et al.	, American Society of							
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		"Liquid flow and heat tr no. 2, p.59-68"	ansfer in	microchannels: A rev	iew", Rostami et	al., Heat	and 7	Technol	ogy; 2000	0; v.18,	
		"Very high heat flux mi al., IEEE Transactions o Packaging, May 1996; v	n Comp	onents, Packaging, and	•				•	oy et	
M	UG	"Convective heat transfo	er in mic	rochannels", Samalam	, Journal of Elec	tronic Ma	terial	s, Vol.	18, pp. 61	1-617,	
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		"Micro heat spreader en Module Conference; Jar			', Shen et al., Pro	ceedings	of the	EEEE	Multi-Ch	ip
		"Microflow devices and v.4, no.4, p.157-171	systems	", Shoji et al., Journal	of Micromechan	ics and M	licroe	nginee	ring; Dec	1994;
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		"Electrokinetic dewatering Sunderland, J Appi Electro				of electro	okineti	c applic	cations",	
M		"High-performance heat si p.126-129	nking for	VLSI", Tuckerman et al	., IEEE Electron D	Device Lef	t; May	1981;	v.EDL-2, r	no. 5,
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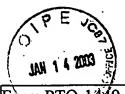


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